Centrality Indicators For Efficient And Scalable Logic Masking

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Objective:

Fight against **counterfeiting** and **illegal copying** of integrated circuits and IP cores.

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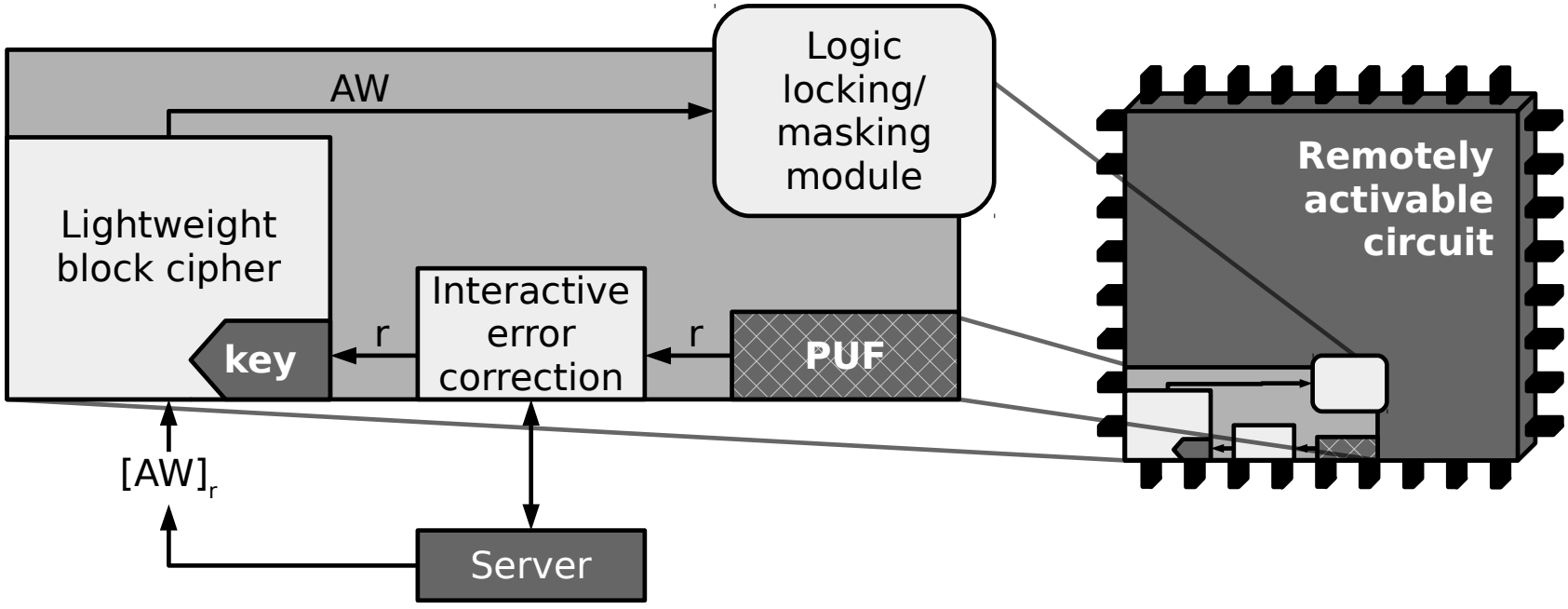

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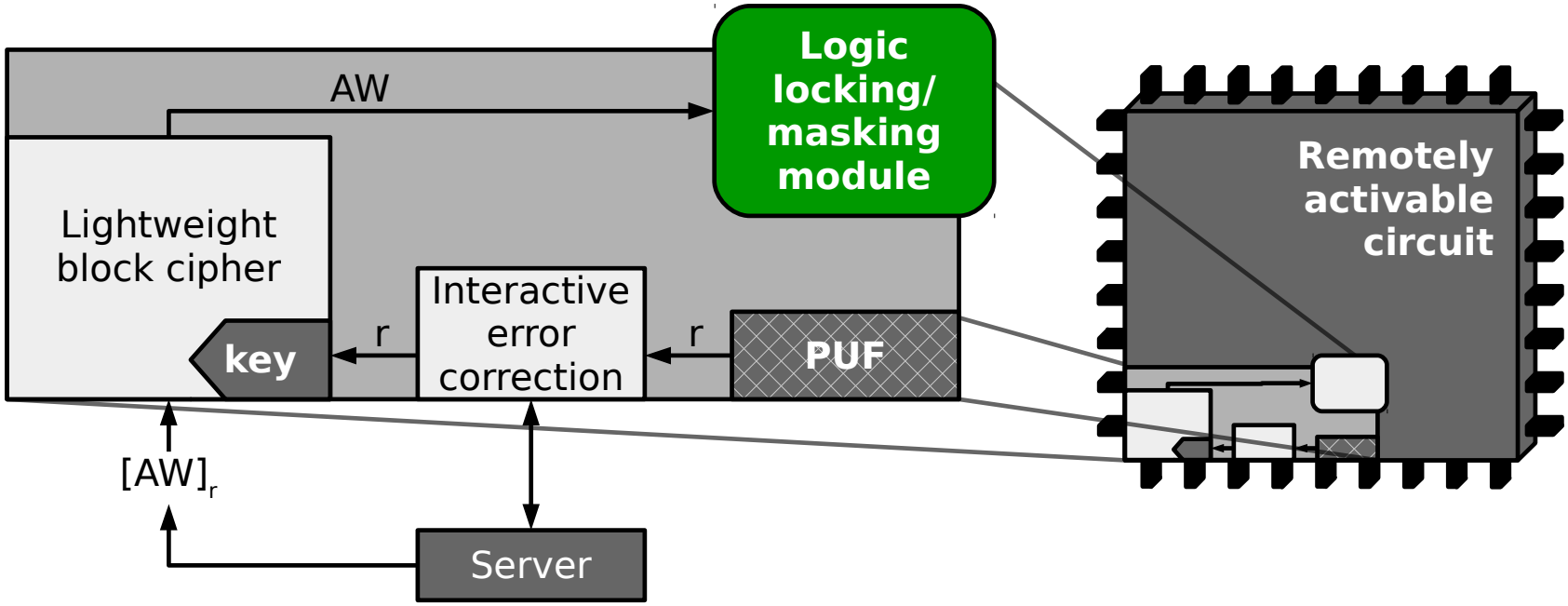

Proposition:

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Solutions:

We want to be able to **controllably**:

- Force the outputs to a fixed logic value: **locking**[1].
- Alter the outputs as much as possible: **masking**[2].

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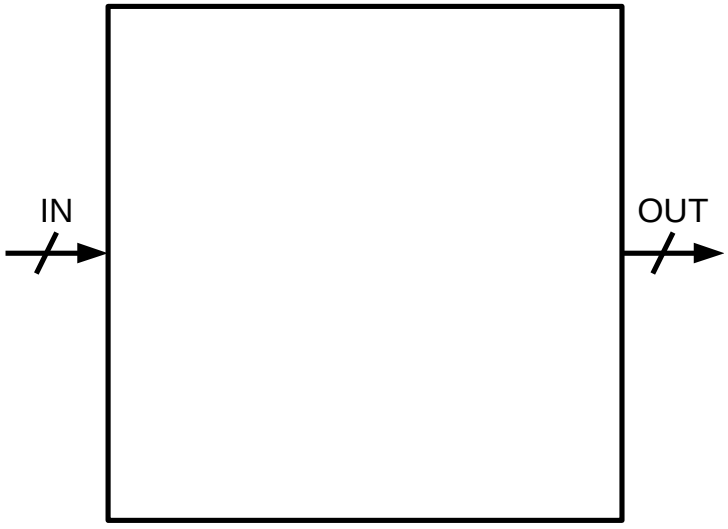
[1] B. Colombier, L. Bossuet, and D. Hély. "Reversible Denial-of-Service by Locking Gates Insertion for IP Cores Design Protection". *Cryptarchi*. 2015.

[2] J. A. Roy, F. Koushanfar, and I. Markov. "EPIC: Ending Piracy of Integrated Circuits". *DATE*. 2008.

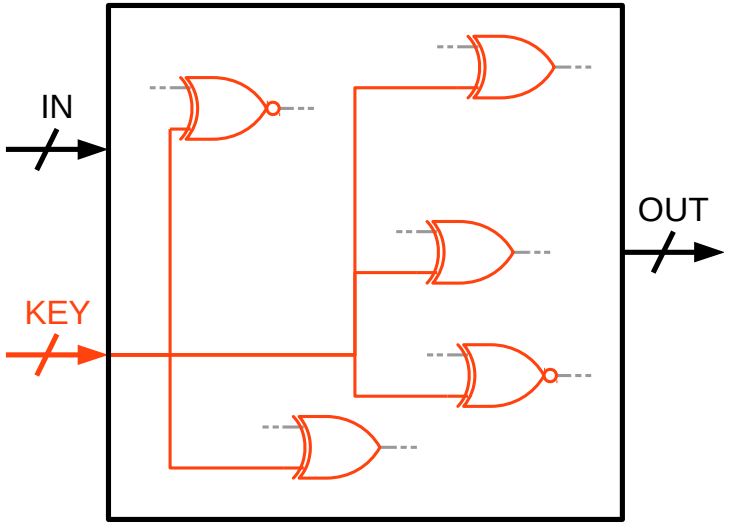
Combinational logic masking

Principle

Insert **XOR/XNOR** gates at **specific** locations in the netlist, so that internal nodes can be controllably inverted to alter the internal state if the wrong activation word is fed.



Original netlist



Masked netlist

Principle

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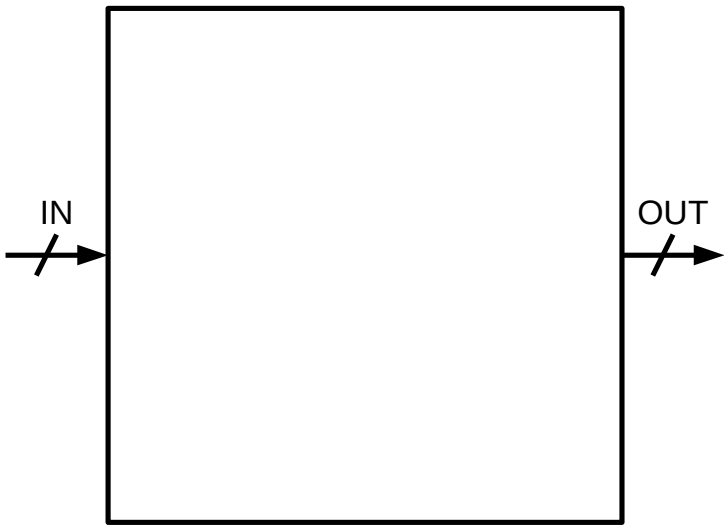

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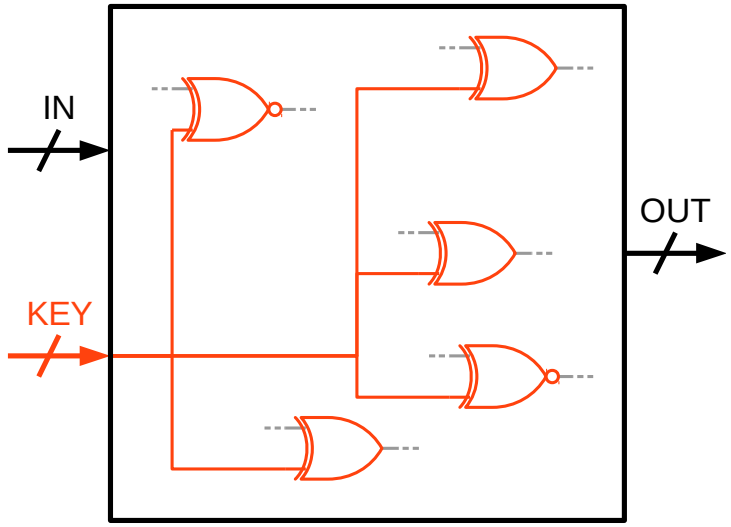

Masked netlist

Done at design time

The process should be as fast as possible.

Metrics to measure the masking efficiency

Notation:

AW: n-bit activation input.

AW_{ref}: Reference activation word.

S: Correct outputs of the netlist.

S_{mod}: Masked outputs of the netlist.

Metrics based on:

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How to **optimise** these metrics ?

Several heuristics exist to select the place of insertion:

Selection heuristic
Random[1]

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Nodes selection heuristics

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Nodes selection heuristics

Several heuristics exist to select the place of insertion:

Selection heuristic	Masking efficiency
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Selection heuristic	Masking efficiency	Computational complexity
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Fan-in/fan-out cones[2]	✗	✓
Random + interf. graph[3]	✗	✓
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Fault analysis[5]	✓	✗

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Towards a better trafe-off between masking efficiency and computational complexity

Centrality: **Importance** of a given vertex inside a graph.

Centrality indicators

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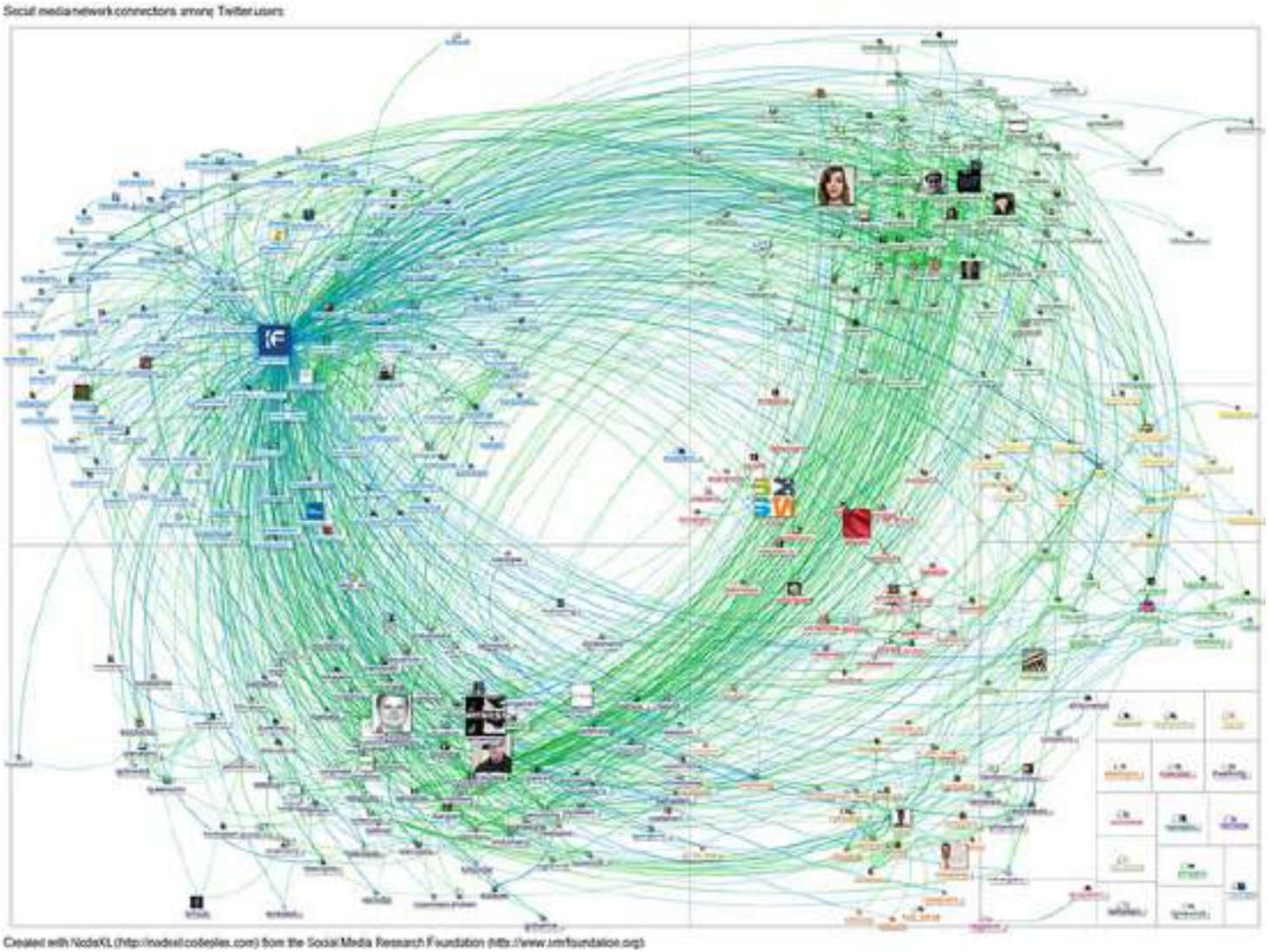
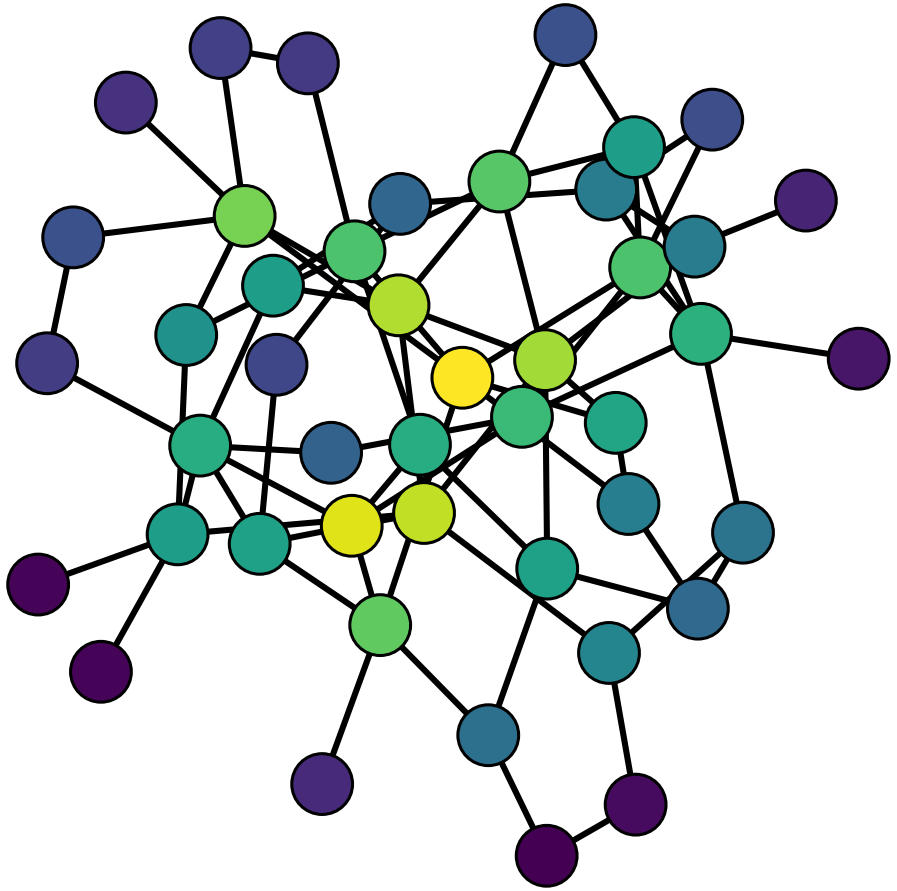


Centrality: **Importance** of a given vertex inside a graph.

Centrality:

- Closeness,



Definition:

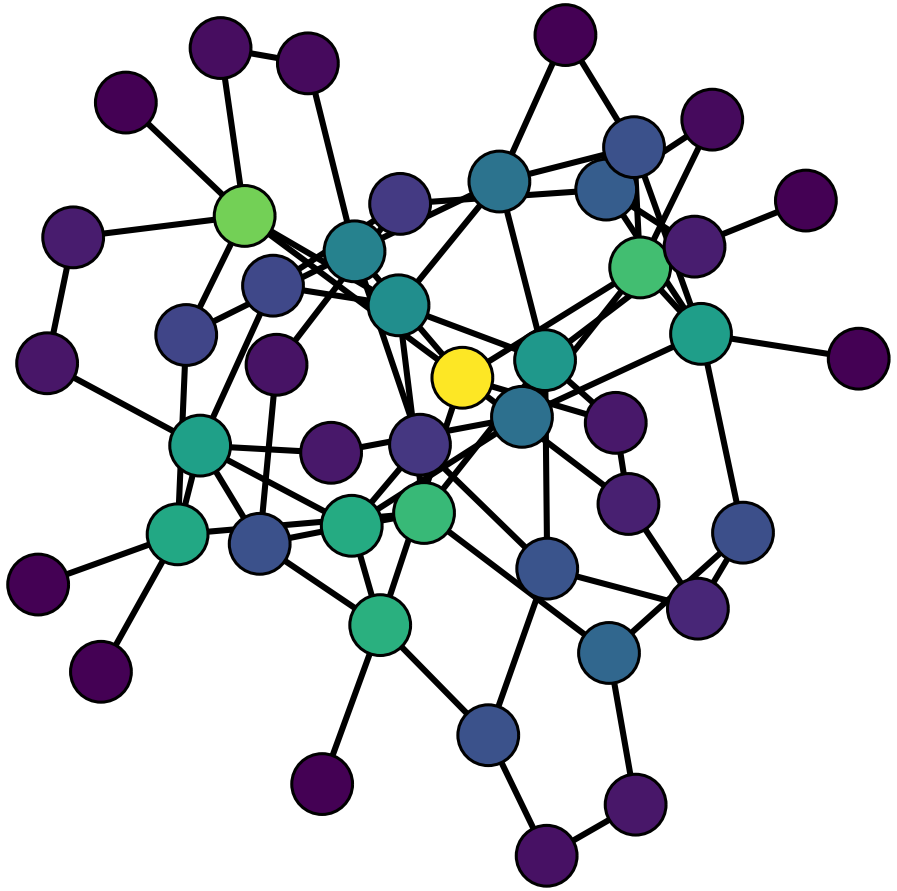
Inverse of the sum of distances to all the other vertices.

$$C(v) = \frac{1}{\sum_{y:y \in V} d(v,y)}$$

Centrality: **Importance** of a given vertex inside a graph.

Centrality:

- Closeness,
- Betweenness,



Definition:

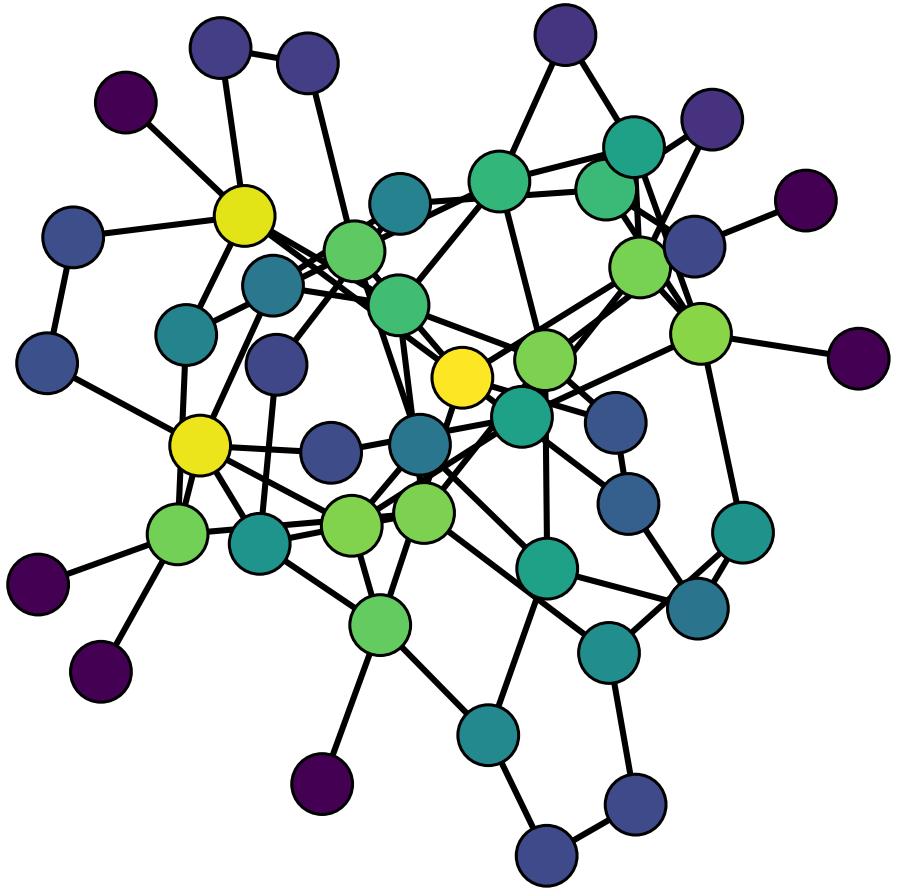
Ratio of shortest paths going through this vertex.

$$C(v) = \sum_{s \neq t \neq v : \{s,t,v\} \in V} \frac{\sigma_{svt}}{\sigma_{st}}$$

Centrality: **Importance** of a given vertex inside a graph.

Centrality:

- Closeness,
- Betweenness,
- Current-flow betweenness,



Definition:

Current flowing through this vertex with others as source and sink.

$$C(v) = \sum_{s \neq t : \{s,t\} \in V} I_v^{(st)}$$

Centrality: **Importance** of a given vertex inside a graph.

Centrality:

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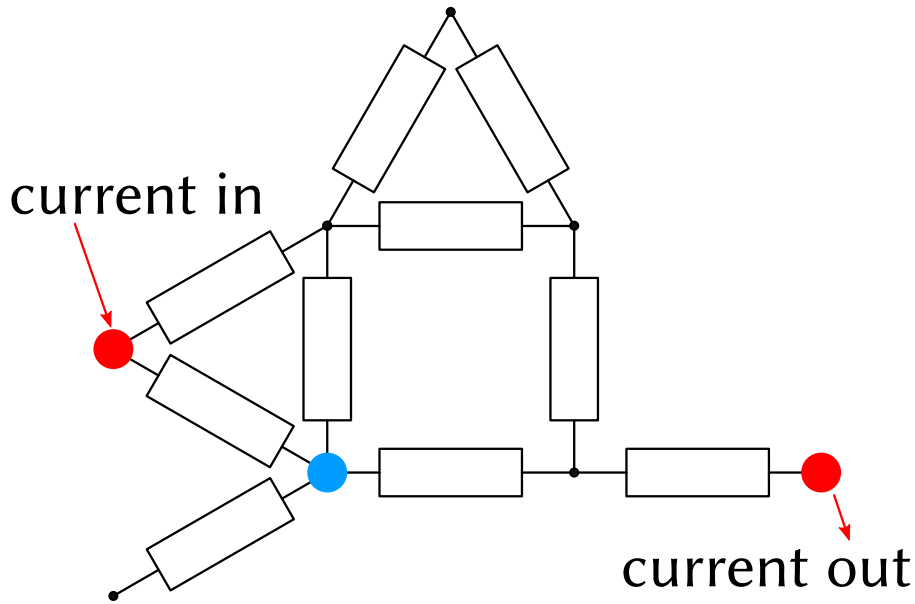

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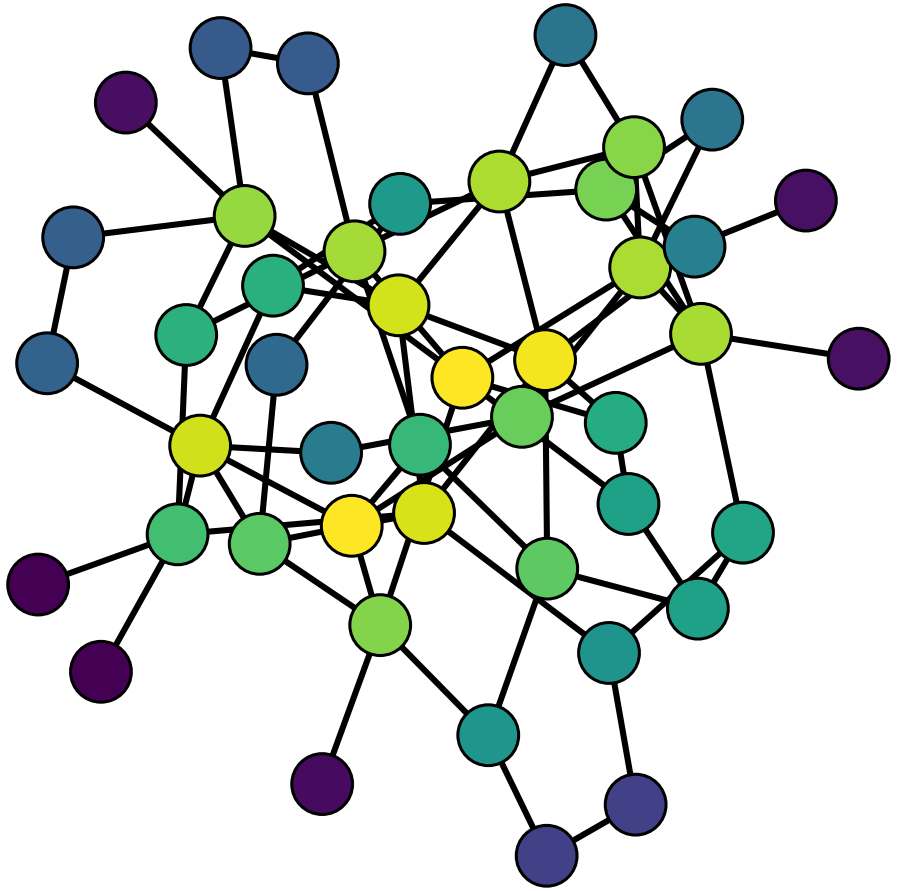
Centrality:

- Closeness,
- Betweenness,
- Current-flow betweenness,
- Current-flow closeness,

Definition:

Sum of effective resistances to all other vertices.



$$C(v) = \frac{1}{\sum_{y:y\in V} p(v)-p(y)} = \frac{1}{\sum_{y:y\in V} R_{eq}(v,y)}$$

Indicators that only account for shortest paths

Closeness, betweenness.

Comparison of centrality indicators

Indicators that only account for shortest paths

Closeness, betweenness.

Indicators that weigh paths according to their length

Current-flow betweenness and closeness centralities.

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Increasing computational complexity

Closeness

↓

Betweenness

↓

Current-flow closeness centrality

↓

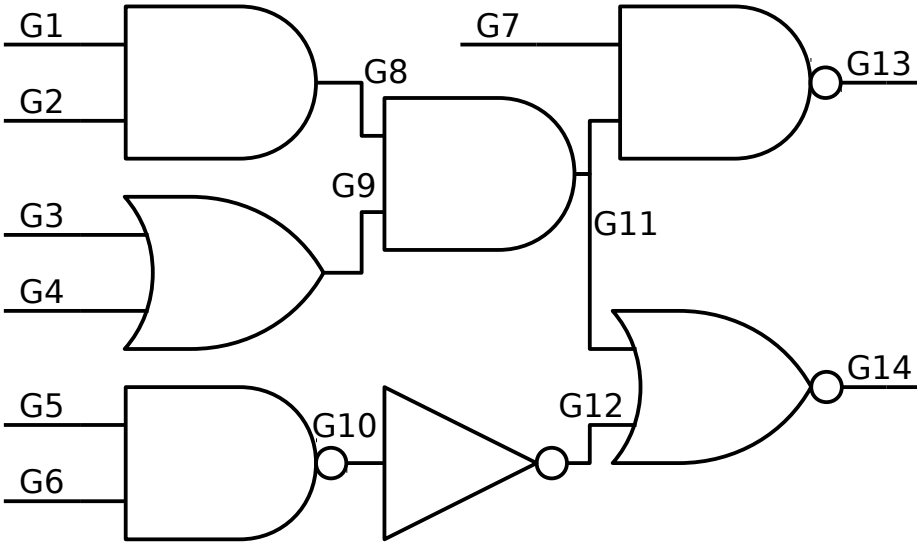
Approximated current-flow betweenness centrality

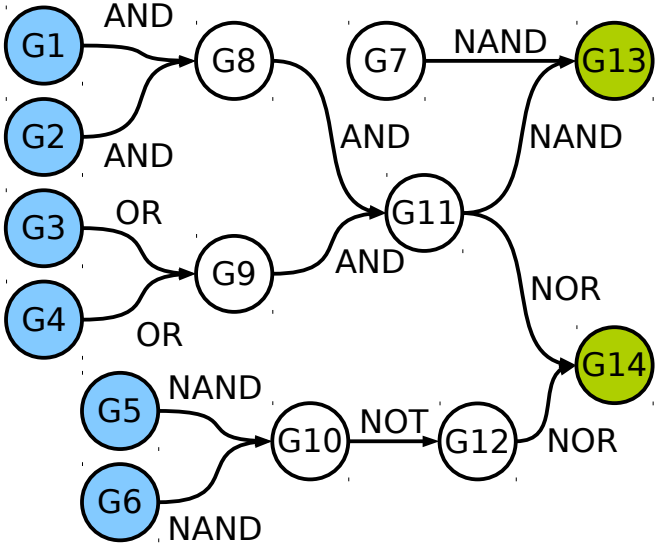
↓

Current-flow betweenness centrality

Convert the netlist into a graph

Nodes $\rightarrow$ vertices
Gates $\rightarrow$ edges





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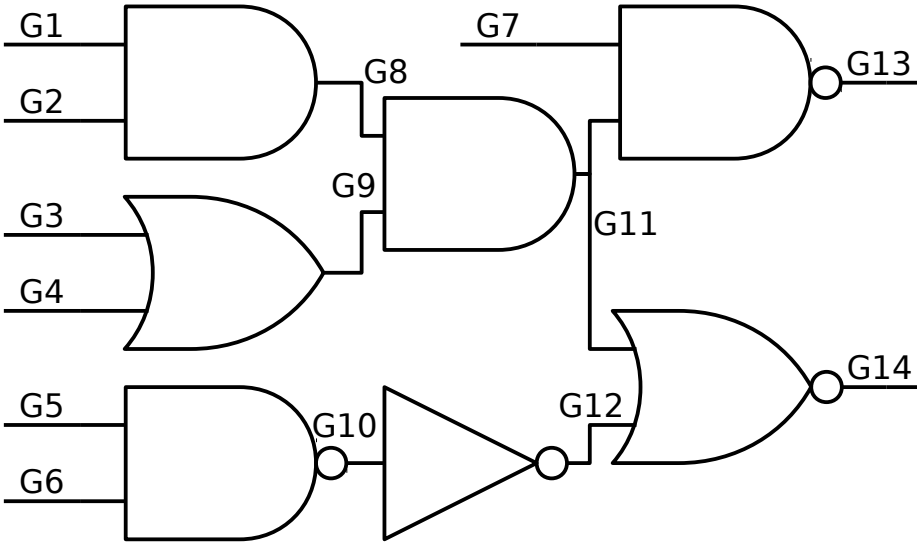
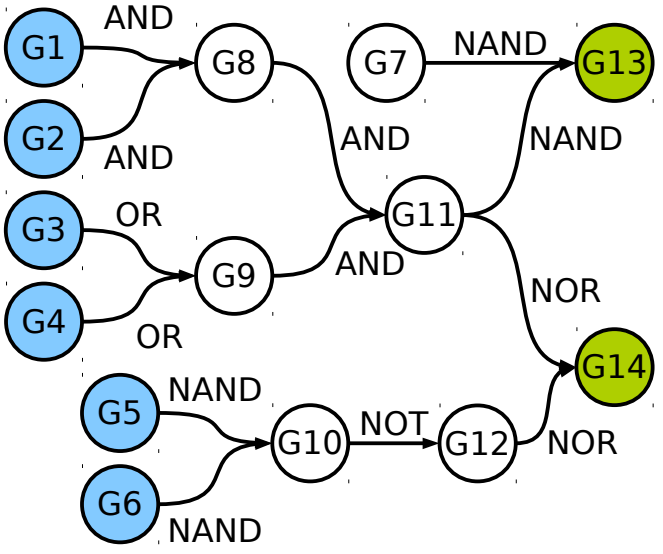
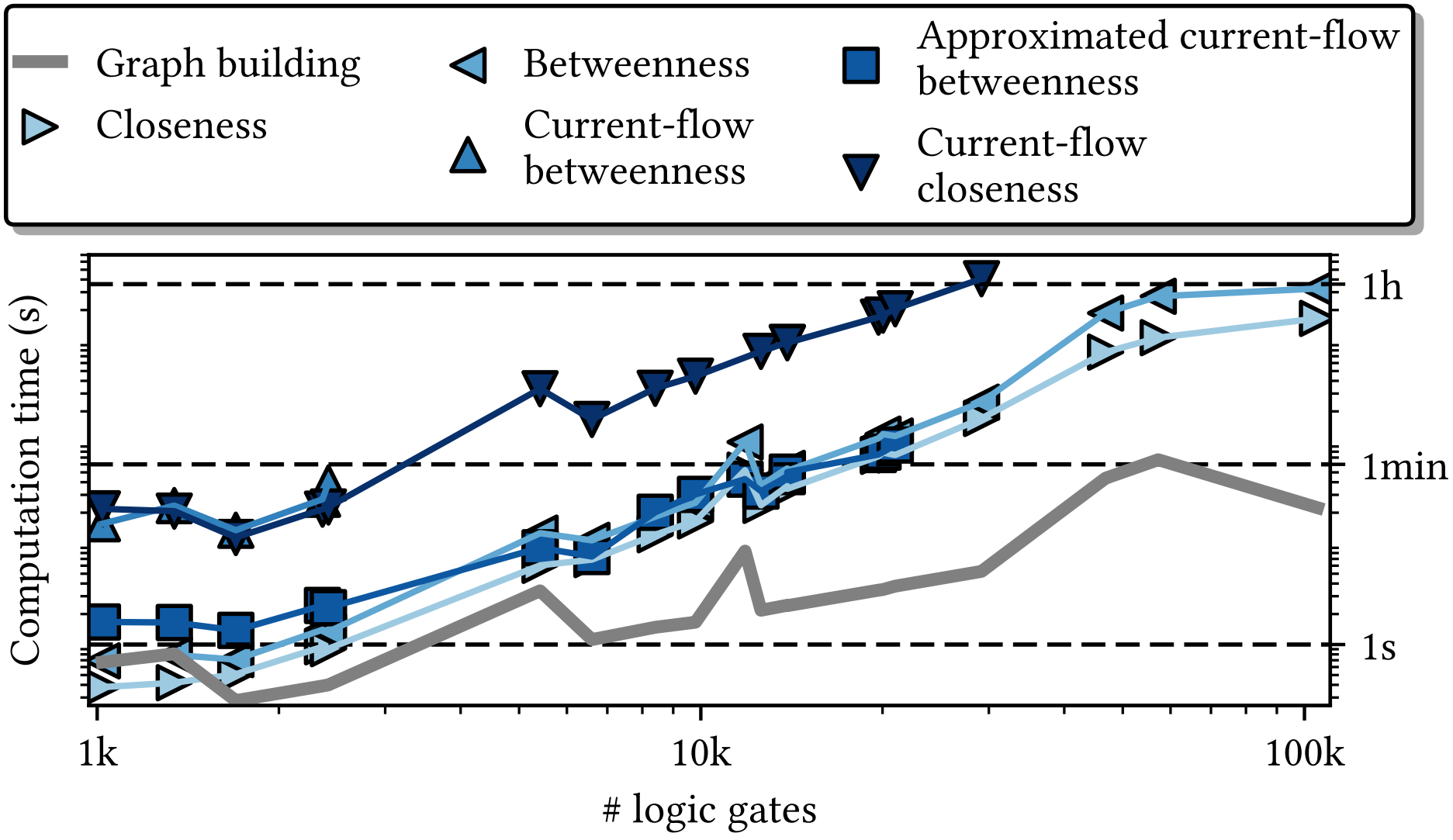
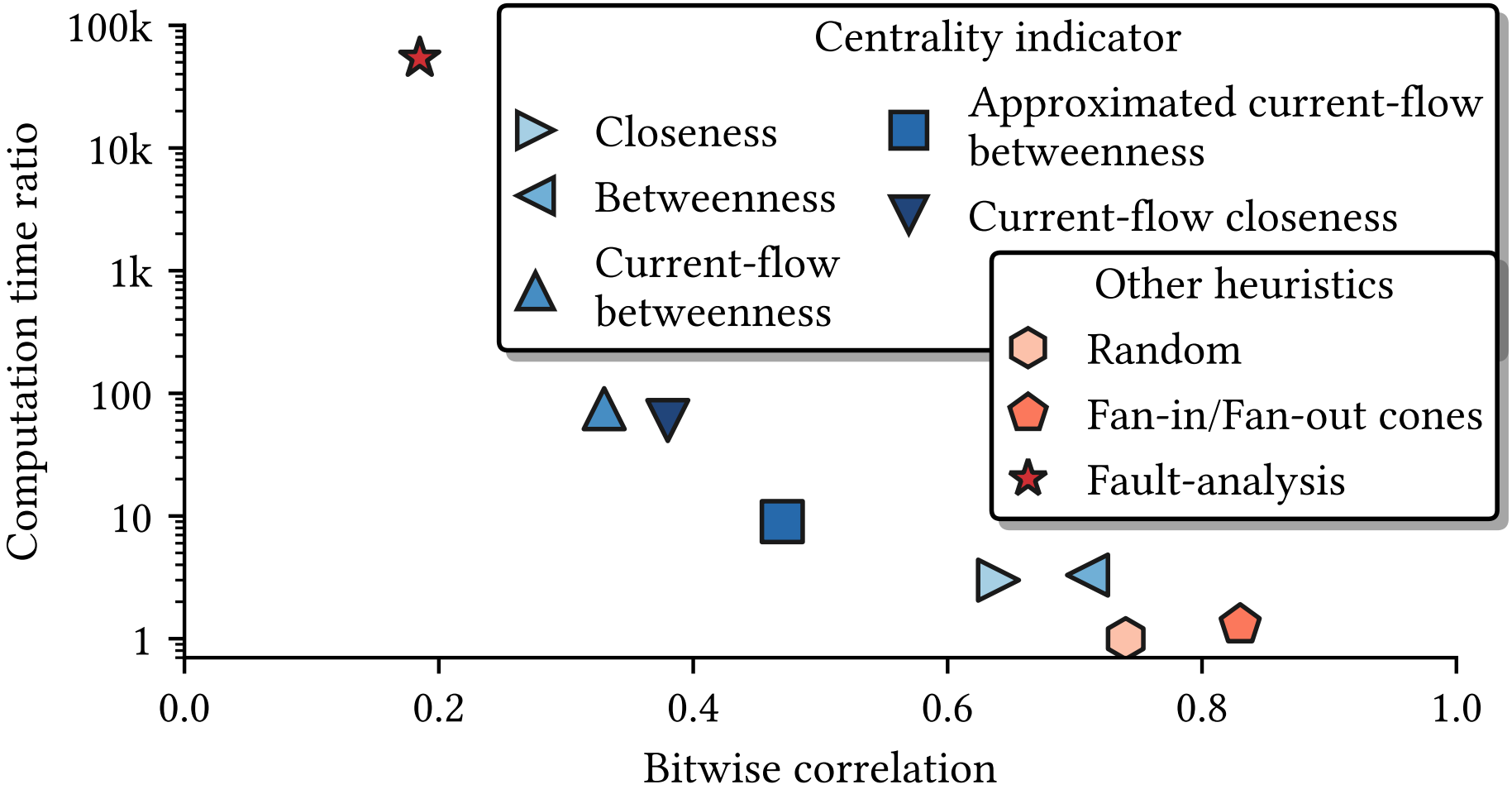




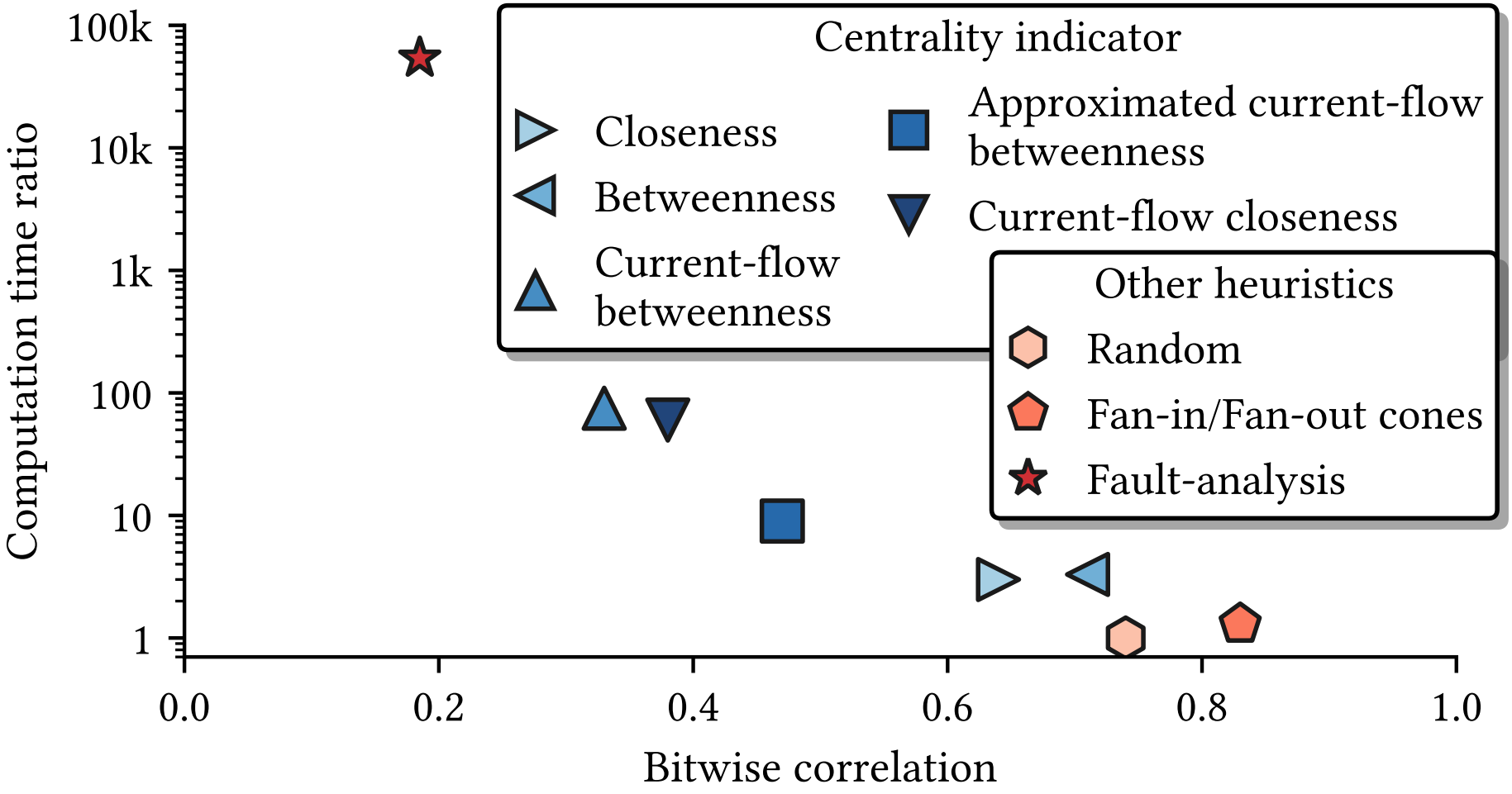
XOR/XNOR gates are inserted on the vertices for which the chosen centrality indicator is the **highest**.

Computation time




Centrality indicator
Closeness
Betweenness
Current-flow betweenness
Approximated current-flow betweenness
Current-flow closeness
Other heuristics
Random
Fan-in/Fan-out cones
Fault-analysis
Computation time ratio
100k
10k
1k
100
10
1
0.0
0.2
0.4
0.6
0.8
1.0
Bitwise correlation

Trade-off



Conclusion

Bitwise correlation is **almost as low** as for the fault analysis-based heuristic, for a run-time **1000x shorter**.

Centrality indicators, in particular current-flow closeness centrality, as node selection heuristic for logic masking:

- allow to **disturb** the outputs **efficiently**,
- have a **manageable** computational **complexity**,
- offer a **better trade-off** than existing heuristics,
- could be **parallelized**...

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— Questions ? —